



HEIWA.014AU

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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| Applicant | : | Shuuske Kantake |) | Group Art Unit 2857 |
| | | |) | |
| Serial No. | : | 10/500,427 |) | |
| | | |) | |
| Filed | : | June 28, 2004 |) | |
| | | |) | |
| For | : | TEST EQUIPMENT FOR LSI AS |) | |
| | | A DEVICE UNDER TEST, |) | |
| | | JITTER ANALYZER, AND PHASE |) | |
| | | DIFFERENCE DETECTOR |) | |
| | | |) | |
| Examiner | : | Mohamed Charioui |) | |
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AMENDMENT

Hon. Commissioner
of Patents and Trademarks
Alexandria, VA 22313-1450

Dear Sir:

This amendment is submitted for the above-identified patent application in response to the office action from the United States Patent and Trademark Office mailed September 22, 2005. Please make the following changes.